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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	310
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	100
Number of Gates	2500
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	132-BCQFP with Tie Bar
Supplier Device Package	132-CQFP (63.5x63.5)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1425a-cq132b

Product Plan

Device/Package	Speed Grade ¹				Application ¹			
	Std.	-1	-2	-3	C	I	M	B
A1415A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓	✓	-
100-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	✓	-
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	✓	-
100-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	-	-	-
A14V15A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	-	-	-	✓	-	-	-
100-Pin Very Thin Quad Flatpack (VQFP)	✓	-	-	-	✓	-	-	-
A1425A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓		
100-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	-	-
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	-	-
132-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	-	-	✓	-	✓	✓
133-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	-	D	D
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	-	-
A14V25A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	-	-	-	✓	-	-	-
100-Pin Very Thin Quad Flatpack (VQFP)	✓	-	-	-	✓	-	-	-
160-Pin Plastic Quad Flatpack (PQFP)	✓	-	-	-	✓	-	-	-
A1440A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓	-	-
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	-	-
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	-	-
175-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	-	-	-
176-Pin Thin Quad Flatpack (TQFP)	✓	✓	D	D	✓	✓	-	-

Notes:

- Applications:
C = Commercial
I = Industrial
M = Military
- Commercial only

Availability:
✓ = Available
P = Planned
- = Not planned
D = Discontinued

Speed Grade:
-1 = Approx. 15% faster than Std.
-2 = Approx. 25% faster than Std.
-3 = Approx. 35% faster than Std.
(-2 and -3 speed grades have been discontinued.)

Plastic Device Resources

Device Series	Logic Modules	Gates	User I/Os							
			PL84	PQ100	PQ160	PQ/RQ208	VQ100	TQ176	BG225*	BG313
A1415	200	1500	70	80	–	–	80	–	–	–
A1425	310	2500	70	80	100	–	83	–	–	–
A1440	564	4000	70	–	131	–	83	140	–	–
A1460	848	6000	–	–	131	167	–	151	168	–
A14100	1377	10000	–	–	–	175	–	–	–	228

Note: *Discontinued

Hermetic Device Resources

Device Series	Logic Modules	Gates	User I/Os							
			PG100*	PG133*	PG175*	PG207	PG257	CQ132	CQ196	CQ256
A1415	200	1500	80	–	–	–	–	–	–	–
A1425	310	2500	–	100	–	–	–	100	–	–
A1440	564	4000	–	–	140	–	–	–	–	–
A1460	848	6000	–	–	–	168	–	–	168	–
A14100	1377	10000	–	–	–	–	228	–	–	228

Note: *Discontinued

Contact your local Microsemi SoC Products Group (formerly Actel) representative for device availability:

<http://www.microsemi.com/soc/contact/default.aspx>.

Logic Modules

ACT 3 logic modules are enhanced versions of the 1200XL family logic modules. As in the 1200XL family, there are two types of modules: C-modules and S-modules (Figure 2-2 and Figure 2-3). The C-module is functionally equivalent to the 1200XL C-module and implements high fanin combinatorial macros, such as 5-input AND, 5-input OR, and so on. It is available for use as the CM8 hard macro. The S-module is designed to implement high-speed sequential functions within a single module.

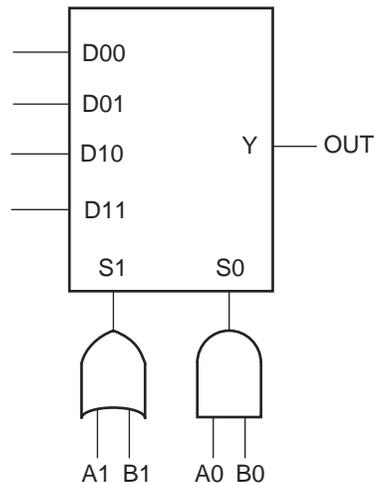


Figure 2-2 • C-Module Diagram

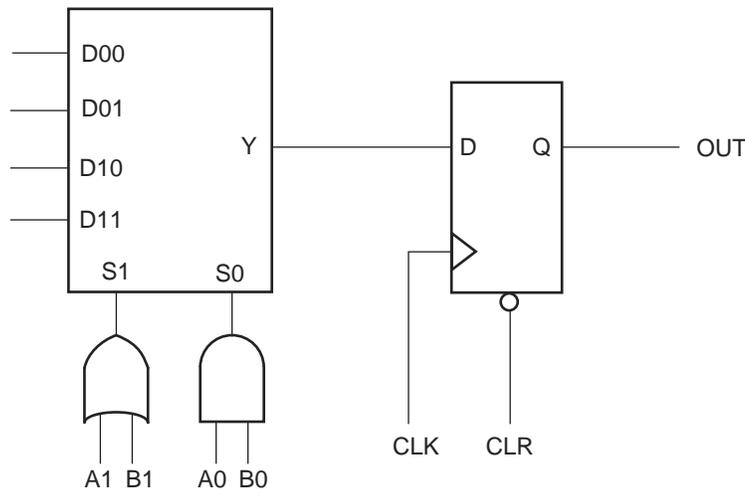


Figure 2-3 • S-Module Diagram

S-modules consist of a full C-module driving a flip-flop, which allows an additional level of logic to be implemented without additional propagation delay. It is available for use as the DFM8A/B and DLM8A/B hard macros. C-modules and S-modules are arranged in pairs called module-pairs. Module-pairs are arranged in alternating patterns and make up the bulk of the array. This arrangement allows the placement software to support two-module macros of four types (CC, CS, SC, and SS). The C-module implements the following function:

$$Y = !S1 * !S0 * D00 + !S1 * S0 * D01 + S1 * !S0 * D10 + S1 * S0 * D11$$

EQ 1

where: $S0 = A0 * B0$ and $S1 = A1 + B1$

5 V Operating Conditions

Table 2-2 • Absolute Maximum Ratings¹, Free Air Temperature Range

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current ²	±20	mA
T _{STG}	Storage temperature	–65 to +150	°C

Notes:

1. Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.
2. Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will forward bias and can draw excessive current.

Table 2-3 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature range*	0 to +70	–40 to +85	–55 to +125	°C
5 V power supply tolerance	±5	±10	±10	%VCC

Note: *Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.

Table 2-4 • Electrical Specifications

Symbol	Parameter	Test Condition	Commercial		Industrial		Military		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
VOH ^{1,2}	High level output	IOH = –4 mA (CMOS)	–	–	3.7	–	3.7	–	V
		IOH = –6 mA (CMOS)	3.84						V
		IOH = –10 mA (TTL) ³	2.40						V
VOL ^{1,2}	Low level output	IOL = +6 mA (CMOS)		0.33		0.4		0.4	V
		IOL = +12 mA (TTL) ³		0.50					
VIH	High level input	TTL inputs	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIL	Low level input	TTL inputs	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
IIN	Input leakage	VI = VCC or GND	–10	+10	–10	+10	–10	+10	µA
IOZ	3-state output leakage	VO = VCC or GND	–10	+10	–10	+10	–10	+10	µA
C _{IO}	I/O capacitance ^{3,4}			10		10		10	pF
ICC(S)	Standby VCC supply current (typical = 0.7 mA)			2		10		20	mA
ICC(D)	Dynamic VCC supply current. See the Power Dissipation section.								

Notes:

1. Microsemi devices can drive and receive either CMOS or TTL signal levels. No assignment of I/Os as TTL or CMOS is required.
2. Tested one output at a time, VCC = minimum.
3. Not tested; for information only.
4. VOUT = 0 V, f = 1 MHz
5. Typical standby current = 0.7 mA. All outputs unloaded. All inputs = VCC or GND.

Package Thermal Characteristics

The device junction to case thermal characteristic is θ_{jc} , and the junction to ambient air characteristic is θ_{ja} . The thermal characteristics for θ_{ja} are shown with two different air flow rates.

Maximum junction temperature is 150°C.

A sample calculation of the absolute maximum power dissipation allowed for a CPGA 175-pin package at commercial temperature and still air is as follows:

$$\frac{\text{Max. junction temp. (°C)} - \text{Max. ambient temp. (°C)}}{\theta_{ja} \text{ °C/W}} = \frac{150\text{°C} - 70\text{°C}}{25\text{°C/W}} = 3.2 \text{ W}$$

EQ 2

Table 2-8 • Package Thermal Characteristics

Package Type*	Pin Count	θ_{jc}	θ_{ja} Still Air	θ_{ja} 300 ft./min.	Units
Ceramic Pin Grid Array	100	20	35	17	°C/W
	133	20	30	15	°C/W
	175	20	25	14	°C/W
	207	20	22	13	°C/W
	257	20	15	8	°C/W
Ceramic Quad Flatpack	132	13	55	30	°C/W
	196	13	36	24	°C/W
	256	13	30	18	°C/W
Plastic Quad Flatpack	100	13	51	40	°C/W
	160	10	33	26	°C/W
	208	10	33	26	°C/W
Very Thin Quad Flatpack	100	12	43	35	°C/W
Thin Quad Flatpack	176	11	32	25	°C/W
Power Quad Flatpack	208	0.4	17	13	°C/W
Plastic Leaded Chip Carrier	84	12	37	28	°C/W
Plastic Ball Grid Array	225	10	25	19	°C/W
	313	10	23	17	°C/W

Note: Maximum power dissipation in still air:

PQ160 = 2.4 W

PQ208 = 2.4 W

PQ100 = 1.6 W

VQ100 = 1.9 W

TQ176 = 2.5 W

PL84 = 2.2 W

RQ208 = 4.7 W

BG225 = 3.2 W

BG313 = 3.5 W

Timing Derating

ACT 3 devices are manufactured in a CMOS process. Therefore, device performance varies according to temperature, voltage, and process variations. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

Table 2-15 • Timing Derating Factor (Temperature and Voltage)

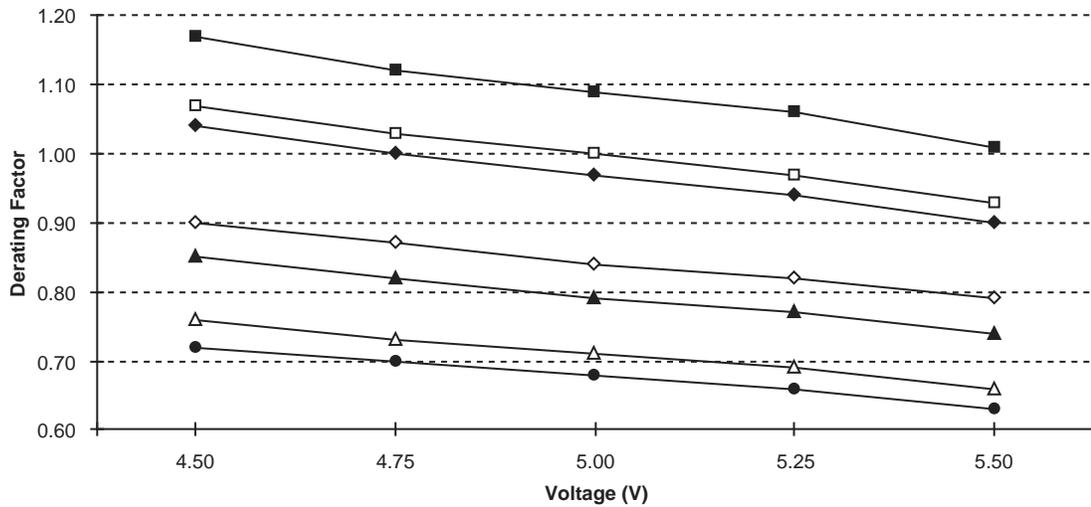
(Commercial Minimum/Maximum Specification) x	Industrial		Military	
	Min.	Max.	Min.	Max.
	0.66	1.07	0.63	1.17

Table 2-16 • Timing Derating Factor for Designs at Typical Temperature ($T_J = 25^\circ\text{C}$) and Voltage (5.0 V)

(Commercial Maximum Specification) x	0.85
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Table 2-17 • Temperature and Voltage Derating Factors (normalized to Worst-Case Commercial, $T_J = 4.75\text{ V}, 70^\circ\text{C}$)

	-55	-40	0	25	70	85	125
4.50	0.72	0.76	0.85	0.90	1.04	1.07	1.117
4.75	0.70	0.73	0.82	0.87	1.00	1.03	1.12
5.00	0.68	0.71	0.79	0.84	0.97	1.00	1.09
5.25	0.66	0.69	0.77	0.82	0.94	0.97	1.06
5.50	0.63	0.66	0.74	0.79	0.90	0.93	1.01



Note: This derating factor applies to all routing and propagation delays.

Figure 2-18 • Junction Temperature and Voltage Derating Curves (normalized to Worst-Case Commercial, $T_J = 4.75\text{ V}, 70^\circ\text{C}$)

A1415A, A14V15A Timing Characteristics (continued)
Table 2-19 • A1415A, A14V15A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module Input Propagation Delays		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ²		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t _{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays²												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t _{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input F-F Data Setup	2.0		2.3		2.5		3.0		3.0		ns
t _{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t _{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t _{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t _{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f _{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes:

- The –2 and –3 speed grades have been discontinued. Please refer to the Product Discontinuation Notices (PDNs) listed below:
 PDN March 2001
 PDN 0104
 PDN 0203
 PDN 0604
 PDN 1004
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1425A, A14V25A Timing Characteristics (continued)

Table 2-24 • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing ¹		–3 Speed ²		–2 Speed ²		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t _{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		6.5		7.5		8.5		10.0		13.0	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		6.5		7.5		8.5		10.0		13.0	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		7.5		7.5		9.0		10.0		13.0	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		11.3		11.3		13.5		15.0		19.5	ns
d _{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing¹												
t _{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t _{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		6.7		7.5		8.5		10.0		13.0	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		6.7		7.5		9.0		10.0		13.0	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		8.9		8.9		10.7		11.8		15.3	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		13.0		13.0		15.6		17.3		22.5	ns
d _{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes: *

1. Delays based on 35 pF loading.
2. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

A1425A, A14V25A Timing Characteristics (continued)
Table 2-25 • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

Dedicated (hardwired) I/O Clock Network		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ILOCKH}	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t _{IOPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{IPOWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{IOSAPW}	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t _{ILOCKSW}	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t _{IOP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{IOMAX}	Maximum Frequency		250		200		150		125		100	MHz
Dedicated (hardwired) Array Clock												
t _{HCKH}	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HCKL}	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{HPWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{HCKSW}	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t _{HP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{HMAX}	Maximum Frequency		250		200		150		125		100	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t _{RCKL}	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t _{RPWH}	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RPWL}	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RCKSW}	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t _{RP}	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f _{RMAX}	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
Clock-to-Clock Skews												
t _{I OHCKSW}	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
t _{I ORCKSW}	I/O Clock to R-Clock Skew (FO = 64) (FO = 80)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	
t _{H RCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 80)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	

Notes:

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Delays based on 35 pF loading.

A1440A, A14V40A Timing Characteristics

Table 2-26 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C¹

Logic Module Propagation Delays ²		-3 Speed ³		-2 Speed ³		-1 Speed		Std. Speed		3.3 V Speed ¹		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t _{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t _{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays⁴												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t _{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUD}	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t _{WCLKA}	Flip-Flop Clock Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t _A	Flip-Flop Clock Input Period	4.0		5.0		6.8		8.0		10.0		ns
f _{MAX}	Flip-Flop Clock Frequency		250		200		150		125		100	MHz

Notes:

- VCC = 3.0 V for 3.3 V specifications.
- For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn} or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
- The -2 and -3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1440A, A14V40A Timing Characteristics (continued)
Table 2-29 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

Dedicated (hardwired) I/O Clock Network		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ILOCKH}	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t _{IOPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{IPOWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{IOSAPW}	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t _{ILOCKSW}	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t _{IOP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{IOMAX}	Maximum Frequency		250		200		150		125		100	MHz
Dedicated (hardwired) Array Clock												
t _{HCKH}	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HCKL}	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{HPWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{HCKSW}	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t _{HP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{HMAX}	Maximum Frequency		250		200		150		125		100	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t _{RCKL}	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t _{RPWH}	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RPWL}	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RCKSW}	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t _{RP}	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f _{RMAX}	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
Clock-to-Clock Skews												
t _{I OHCKSW}	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
t _{I ORCKSW}	I/O Clock to R-Clock Skew (FO = 64) (FO = 144)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	
t _{H RCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 144)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	

Notes:

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Delays based on 35 pF loading.

A1460A, A14V60A Timing Characteristics (continued)

Table 2-32 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing ¹		–3 Speed ²		–2 Speed ²		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t _{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.8		8.7		9.9		11.6		15.1	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.0		9.0		10.0		11.5		15.0	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		12.8		12.8		15.3		17.0		22.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing¹												
t _{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t _{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		10.4		10.4		12.1		13.8		17.9	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		14.5		14.5		17.4		19.3		25.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes:

1. Delays based on 35 pF loading.
2. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

A14100A, A14V100A Timing Characteristics (continued)

Table 2-36 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing ¹		–3 Speed ²		–2 Speed ²		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t _{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.5		9.5		10.5		12.0		15.6	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		12.8		12.8		15.3		17.0		22.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing¹												
t _{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t _{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.0		12.0		15.6	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		10.4		10.4		12.4		13.8		17.9	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		14.5		14.5		17.4		19.3		25.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes: *

- Delays based on 35 pF loading.
- The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

Pin Descriptions

CLKA **Clock A (Input)**

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

CLKB **Clock B (Input)**

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

GND **Ground**

LOW supply voltage.

HCLK **Dedicated (Hard-wired) Array Clock (Input)**

Clock input for sequential modules. This input is directly wired to each S-Module and offers clock speeds independent of the number of S-Modules being driven. This pin can also be used as an I/O.

I/O **Input/Output (Input, Output)**

The I/O pin functions as an input, output, three-state, or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/O pins are tristated by the Designer Series software.

IOCLK **Dedicated (Hard-wired) I/O Clock (Input)**

Clock input for I/O modules. This input is directly wired to each I/O module and offers clock speeds independent of the number of I/O modules being driven. This pin can also be used as an I/O.

IOPCL **Dedicated (Hard-wired) I/O Preset/Clear (Input)**

Input for I/O preset or clear. This global input is directly wired to the preset and clear inputs of all I/O registers. This pin functions as an I/O when no I/O preset or clear macros are used.

MODE **Mode (Input)**

The MODE pin controls the use of diagnostic pins (DCLK, PRA, PRB, SDI). When the MODE pin is HIGH, the special functions are active. When the MODE pin is LOW, the pins function as I/Os. To provide Actionprobe capability, the MODE pin should be terminated to GND through a 10K resistor so that the MODE pin can be pulled high when required.

NC **No Connection**

This pin is not connected to circuitry within the device.

PRA **Probe A (Output)**

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

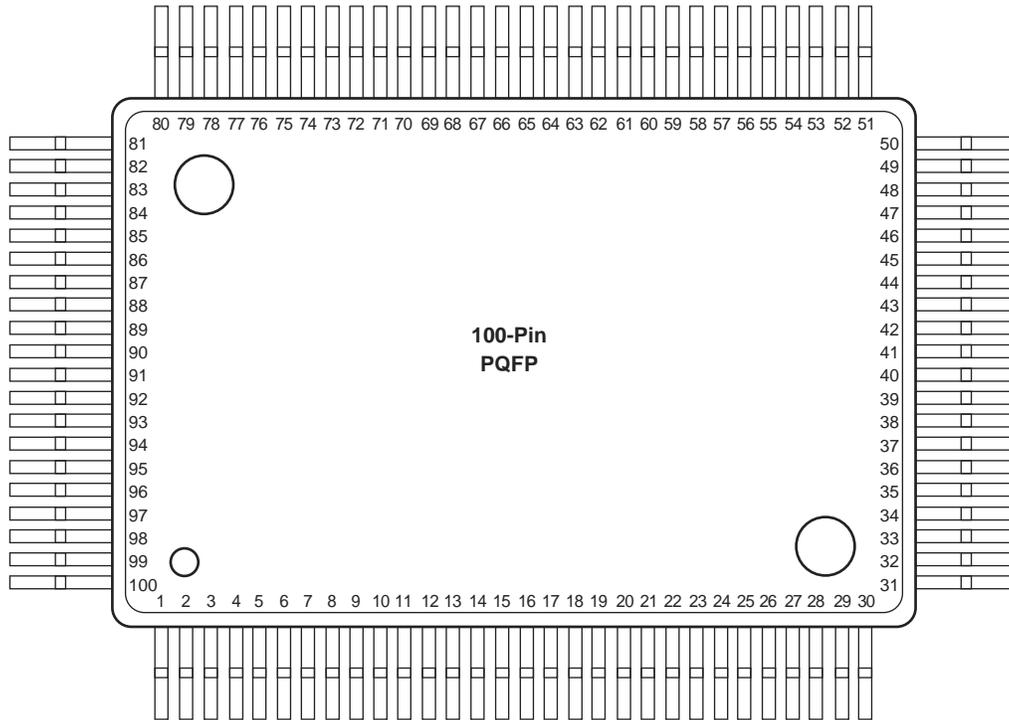
PRB **Probe B (Output)**

The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

SDI **Serial Data Input (Input)**

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

PQ100



Note: This is the top view of the package.

Note

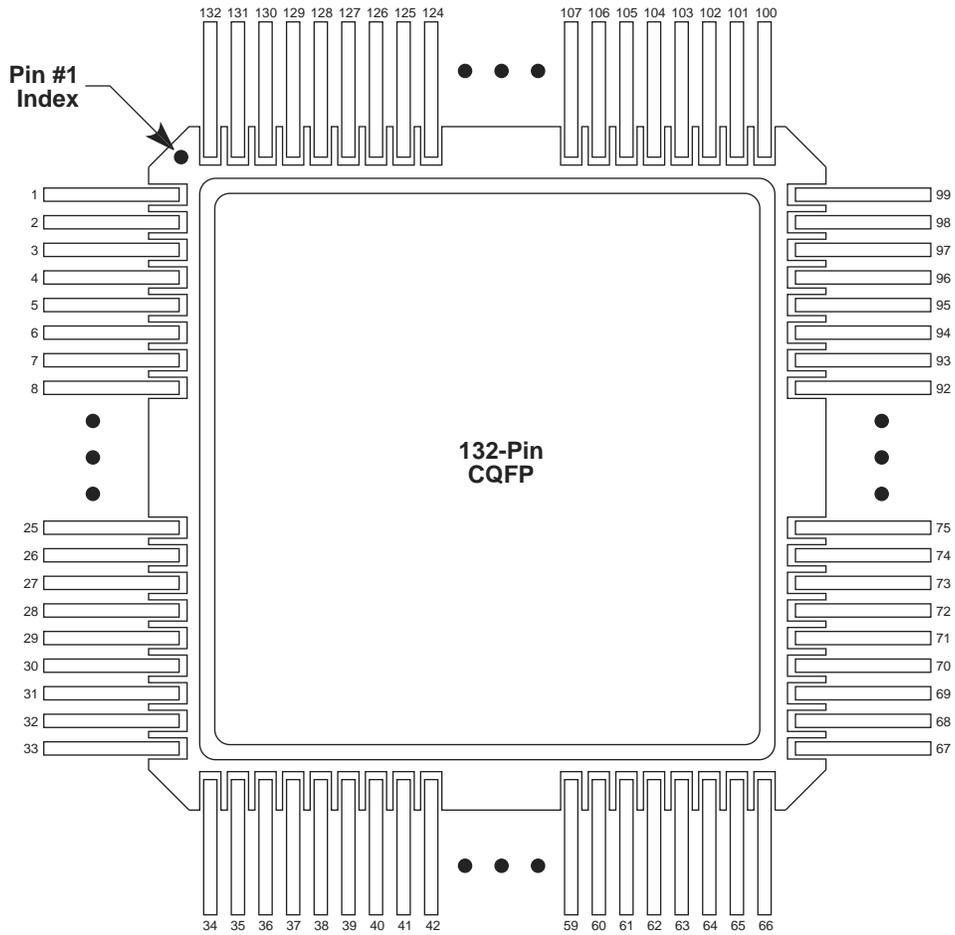
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

VQ100			
Pin Number	A1415, A14V15 Function	A1425, A14V25 Function	A1440, A14V40 Function
1	GND	GND	GND
2	SDI, I/O	SDI, I/O	SDI, I/O
7	MODE	MODE	MODE
8	VCC	VCC	VCC
9	GND	GND	GND
20	VCC	VCC	VCC
21	NC	I/O	I/O
34	PRB, I/O	PRB, I/O	PRB, I/O
35	VCC	VCC	VCC
36	GND	GND	GND
37	VCC	VCC	VCC
39	HCLK, I/O	HCLK, I/O	HCLK, I/O
49	SDO	SDO	SDO
50	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
51	GND	GND	GND
57	VCC	VCC	VCC
58	VCC	VCC	VCC
67	VCC	VCC	VCC
68	GND	GND	GND
69	GND	GND	GND
74	NC	I/O	I/O
75	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
87	CLKA, I/O	CLKA, I/O	CLKA, I/O
88	CLKB, I/O	CLKB, I/O	CLKB, I/O
89	VCC	VCC	VCC
90	VCC	VCC	VCC
91	GND	GND	GND
92	PRA, I/O	PRA, I/O	PRA, I/O
93	NC	I/O	I/O
100	DCLK, I/O	DCLK, I/O	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

CQ132



Note: This is the top view

Note

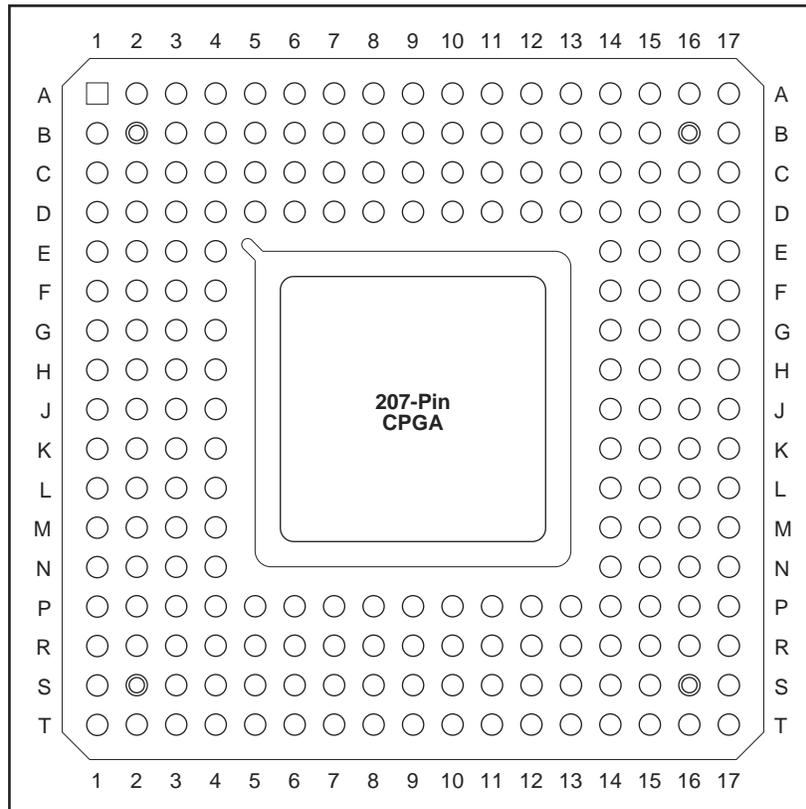
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG100	
A1415 Function	Location
CLKA or I/O	C7
CLKB or I/O	D6
DCLK or I/O	C4
GND	C3, C6, C9, E9, F3, F9, J3, J6, J8, J9
HCLK or I/O	H6
IOCLK or I/O	C10
IOPCL or I/O	K9
MODE	C2
PRA or I/O	A6
PRB or I/O	L3
SDI or I/O	B3
SDO	L9
VCC	B6, B10, E11, F2, F10, G2, K2, K6, K10

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG100 package has been discontinued.

PG207



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG207	
A1460 Function	Location
CLKA or I/O	K1
CLKB or I/O	J3
DCLK or I/O	E4
GND	C14, D4, D5, D9, D14, J4, J14, P3, P4, P7, P9, P14, R15
HCLK or I/O	J15
IOCLK or I/O	P5
IOPCL or I/O	N14
MODE	D7
NC	A1, A2, A16, A17, B1, B17, C1, C2, S1, S3, S17, T1, T2, T16, T17
PRA or I/O	H1
PRB or I/O	K16
SDI or I/O	C3
SDO	P15
VCC	B2, B9, B16, D11, J2, J16, P12, S2, S9, S16, T5

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.